United States Patent [19]

Jones et al.

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[45] **Date of Patent: ** Jul. 23, 1991**

[54] **INTEGRATED CIRCUIT TEST CLIP**

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[73] Assignee: **John Fluke Mfg. Co., Inc.,** Everett, Wash.

[**] Term: **14 Years**

[21] Appl. No.: **77,778**

[22] Filed: **Jul. 24, 1987**

[52] **U.S. Cl.** **D13/146**

[58] **Field of Search** .... D13/133, 146, 199; 324/158 P, 158 F, 72.5; 439/70, 353

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[57] **CLAIM**

The ornamental design for an integrated circuit test clip, as shown and described.

DESCRIPTION

FIG. 1 is a perspective view of an integrated circuit test clip, showing our new design;

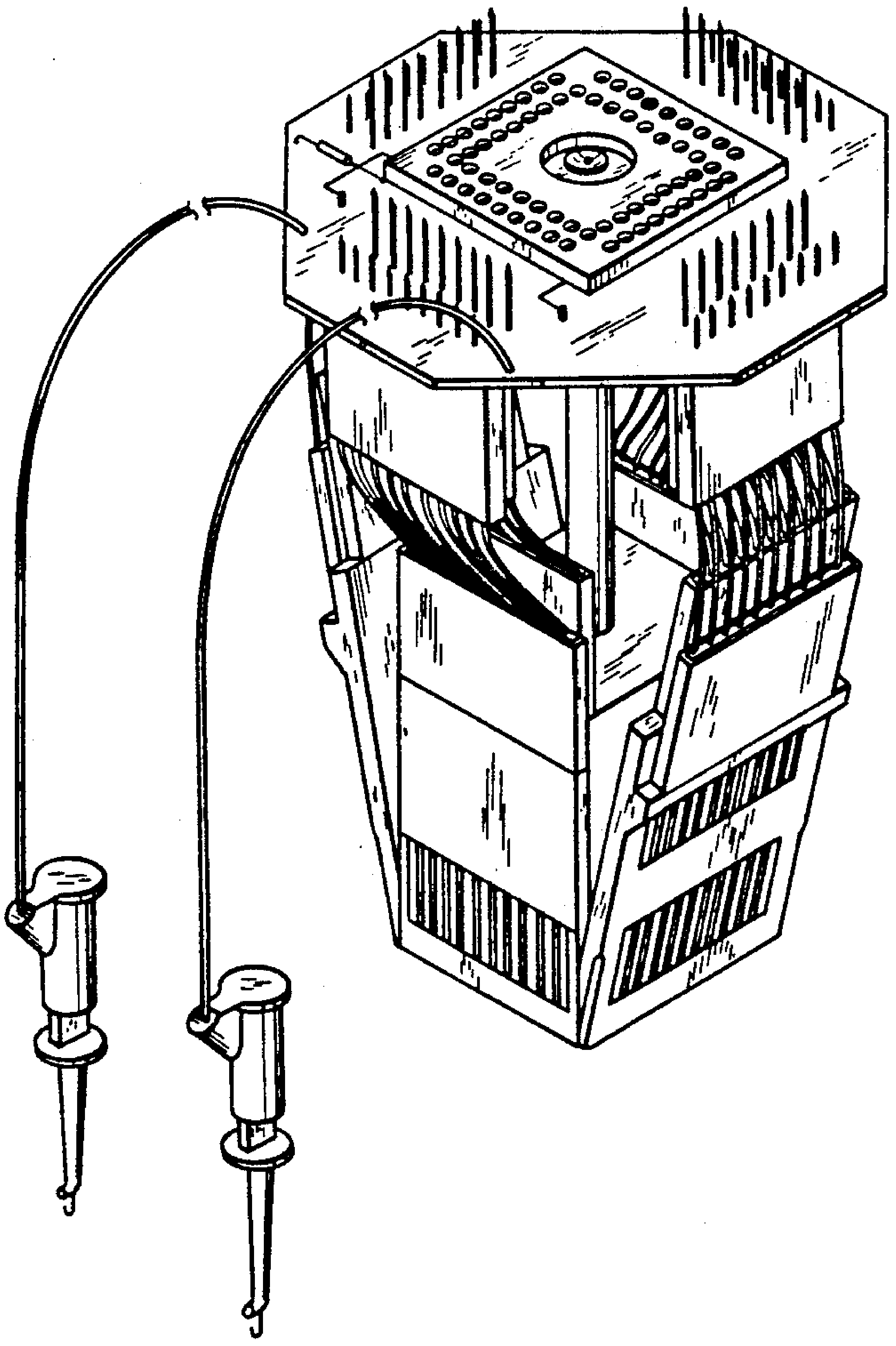
FIG. 2 is a side elevation view thereof, the opposite side being substantially identical to that shown;

FIG. 3 is a side elevation view thereof, orthogonal to the view shown in FIG. 2, the opposite side being substantially identical to that shown;

FIG. 4 is a top plan view thereof; and

FIG. 5 is a bottom plan view thereof.

The cables have been broken away in FIGS. 1-4 to indicate indeterminate length.



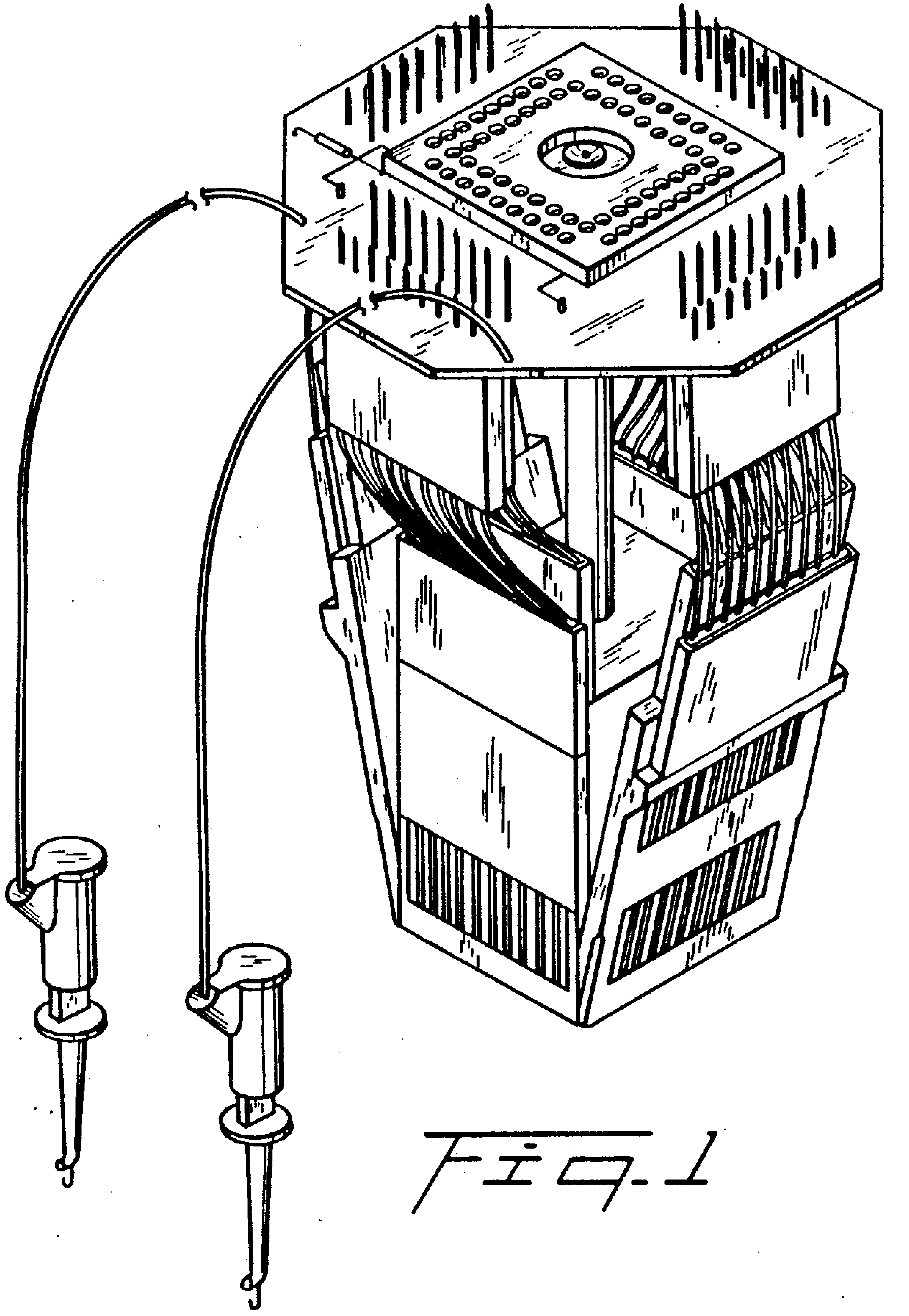


FIG. 1

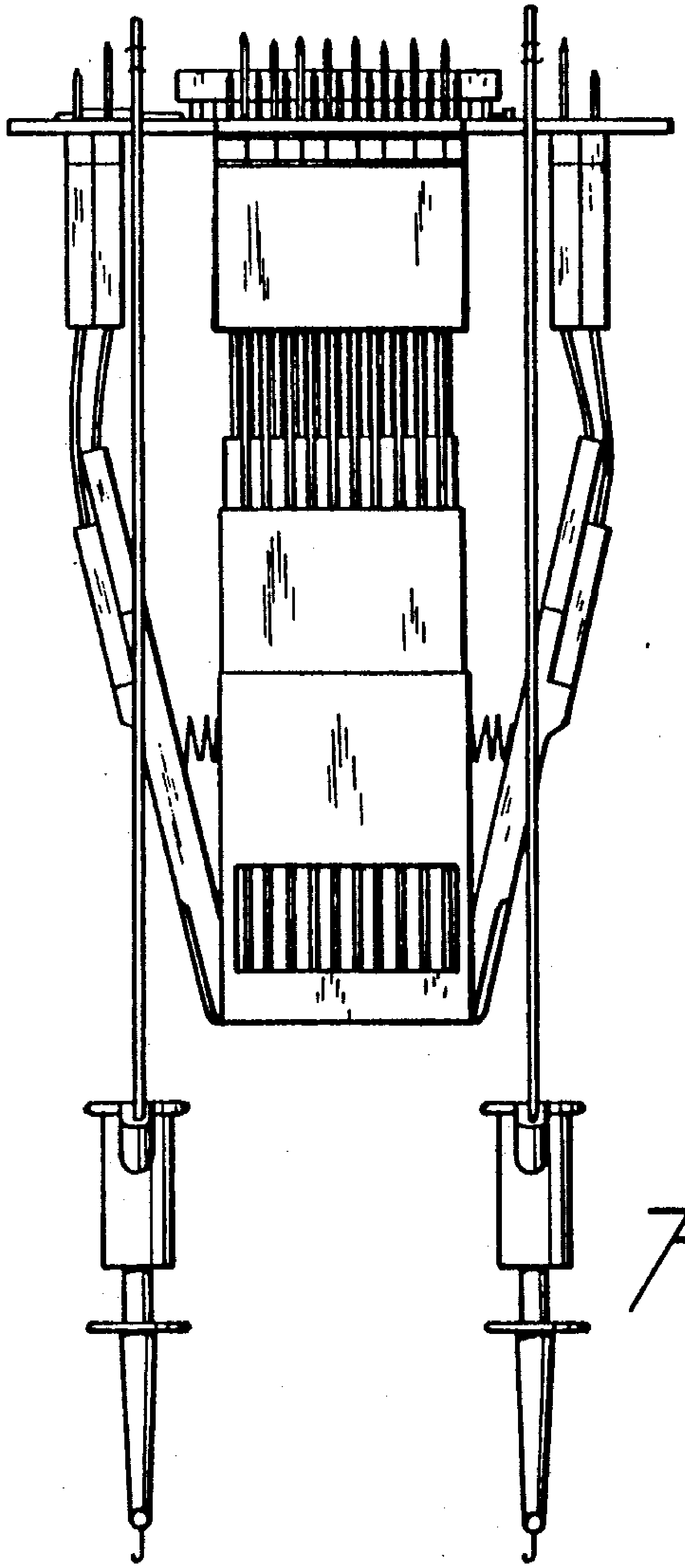


FIG. 2

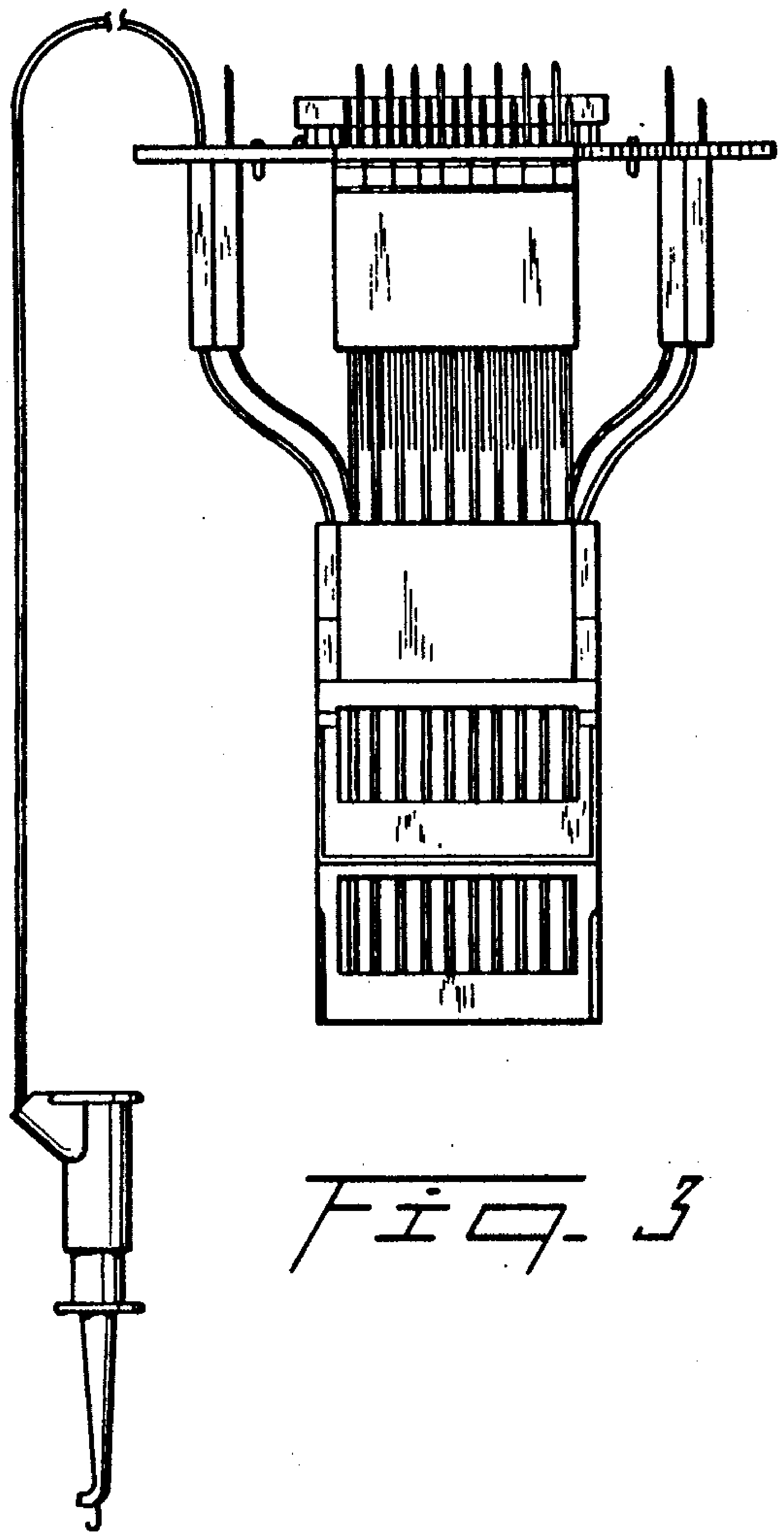


FIG. 3

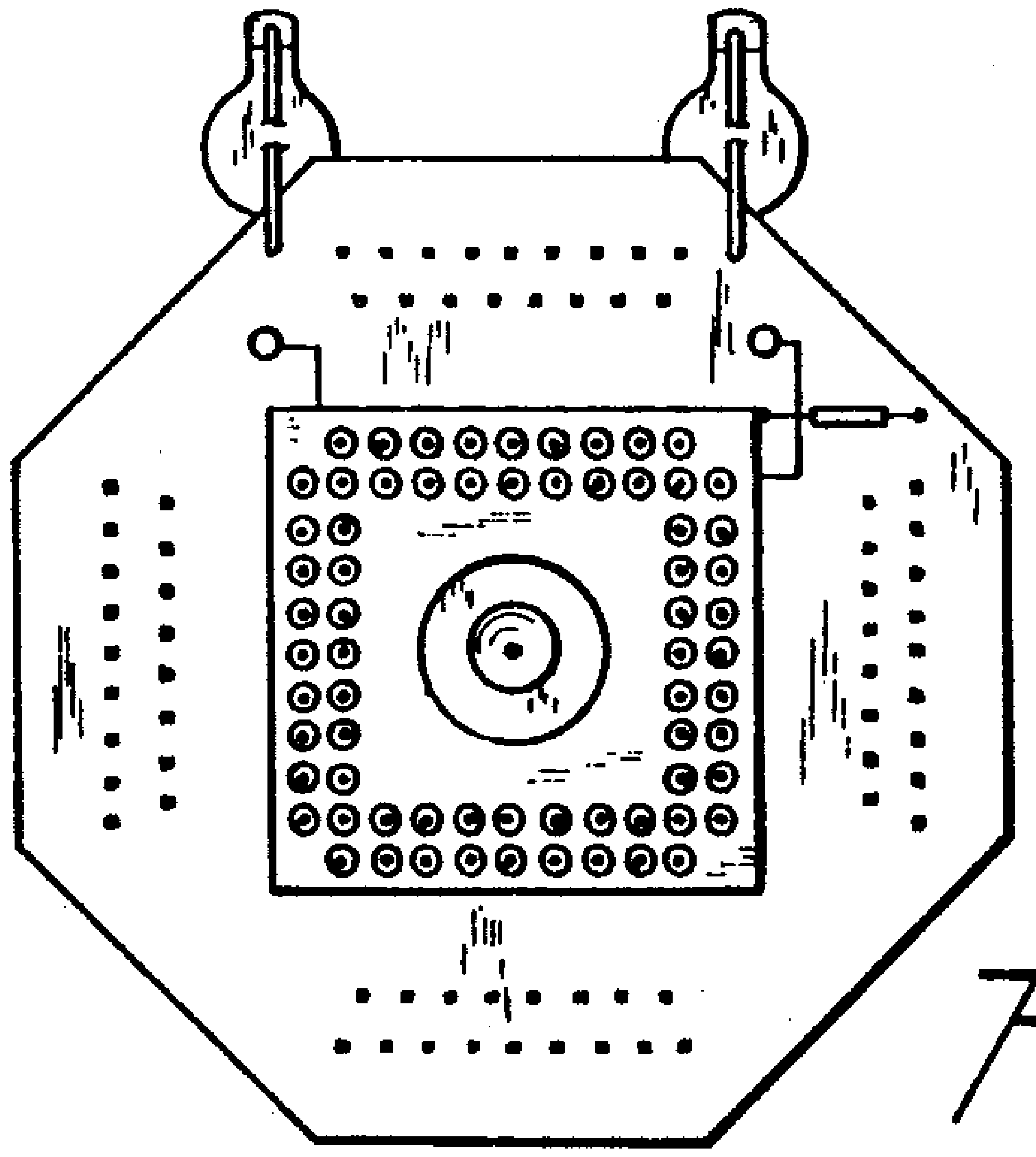


FIG. 4

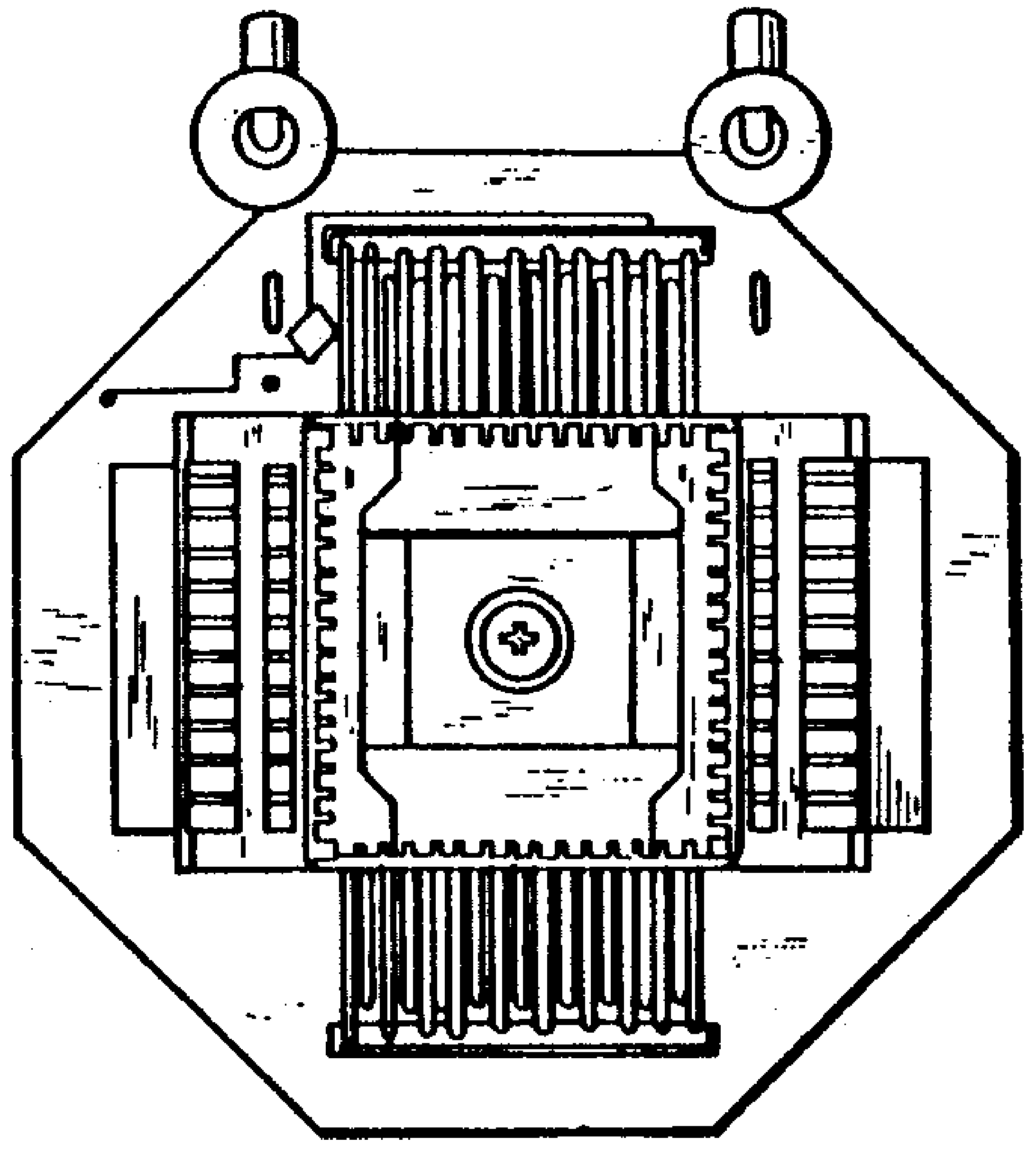


FIG. 5